



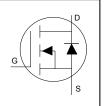
Application

- Brushed Motor drive applications
- BLDC Motor drive applications
- Battery powered circuits
- Half-bridge and full-bridge topologies
- Synchronous rectifier applications
- Resonant mode power supplies
- OR-ing and redundant power switches
- DC/DC and AC/DC converters
- DC/AC Inverters

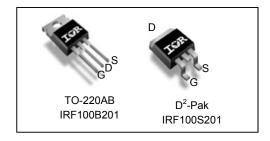
Benefits

- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and dI/dt Capability
- Lead-Free, RoHS Compliant, Halogen-Free





V _{DSS}	100V	
R _{DS(on)} typ.	$3.5 m\Omega$	
max	4.2mΩ	
D (Silicon Limited)	192A	



G	D	S
Gate	Drain	Source

Dage next number	Standard Pack		Oudevehle Deut Neumber	
Base part number	Package Type	Form	Quantity	Orderable Part Number
IRF100B201	TO-220	Tube	50	IRF100B201
IRF100S201	D ² -Pak	Tape and Reel	800	IRF100S201

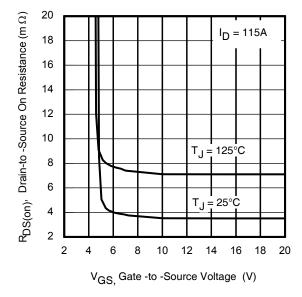


Fig 1. Typical On– Resistance vs. Gate Voltage

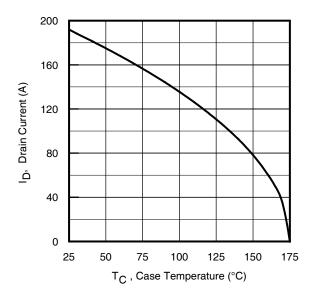


Fig 2. Maximum Drain Current vs. Case Temperature



Absolute Maximum Rating

Symbol	Parameter	Max.	Units
I_D @ T_C = 25°C	Continuous Drain Current, V _{GS} @ 10V	192	
I_D @ T_C = 100°C	I _D @ T _C = 100°C Continuous Drain Current, V _{GS} @ 10V		Α
I _{DM}	Pulsed Drain Current ①	690	
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	441	W
	Linear Derating Factor	2.9	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to + 175	°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	
	Mounting Torque, 6-32 or M3 Screw	10 lbf·in (1.1 N·m)	

Avalanche Characteristics

E _{AS (Thermally limited)}	Single Pulse Avalanche Energy ②	567	
E _{AS (Thermally limited)}	Single Pulse Avalanche Energy	1005	mJ
E _{AS (tested)}	Single Pulse Avalanche Energy Tested Value ®	240	
I _{AR}	Avalanche Current ①	See Fig 15, 15, 23a, 23b	A
E _{AR}	Repetitive Avalanche Energy ①	See Fig. 15, 15, 25a, 25b	mJ

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ூ		0.34	
$R_{\theta CS}$	Case-to-Sink, Flat Greased Surface	0.50		°C/\\/
$R_{ heta JA}$	Junction-to-Ambient		62	°C/W
$R_{ hetaJA}$	Junction-to-Ambient (PCB Mount) ®		40	

Static @ T_J = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_{D} = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.1		V/°C	Reference to 25°C, I _D = 5mA ①
R _{DS(on)}	Static Drain-to-Source On-Resistance		3.5	4.2	mΩ	V _{GS} = 10V, I _D = 115A
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
	Dunin to Course Looks as Course			20	^	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}$
I _{DSS}	Drain-to-Source Leakage Current			250	μA	$V_{DS} = 80V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V
I _{GSS}	Gate-to-Source Reverse Leakage			-100	IIA	$V_{GS} = -20V$
R_G	Gate Resistance		2.2		Ω	

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- $\label{eq:local_spin_spin} \ensuremath{\Im} \quad I_{SD} \leq 115 A, \; di/dt \leq 1400 A/\mu s, \; V_{DD} \leq V_{(BR)DSS}, \; T_J \leq 175 ^{\circ} C.$
- 4 Pulse width $\leq 400 \mu s$; duty cycle $\leq 2\%$.
- © Coss eff. (TR) is a fixed capacitance that gives the same charging time as Coss while VDS is rising from 0 to 80% VDSS.
- © Coss eff. (ER) is a fixed capacitance that gives the same energy as Coss while VDS is rising from 0 to 80% VDSS.
- When mounted on 1 inch square PCB (FR-4). Please refer to AN-994 for more details: http://www.irf.com/technical-info/appnotes/an-994.pdf
- 9 Limited by T_{Jmax} , starting T_J = 25°C, L = 1.0mH, R_G = 50 Ω , I_{AS} = 45A, V_{GS} =10V.
- \odot This value determined from sample failure population, starting T_J =25°C, L= 86μH, R_G = 50Ω, I_{AS} =115A, V_{GS} =10V.



Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
gfs	Forward Transconductance	278			S	$V_{DS} = 10V, I_{D} = 115A$
Q_g	Total Gate Charge		170	255		I _D = 115A
Q_{gs}	Gate-to-Source Charge		46		nC	V _{DS} = 50V
Q_{gd}	Gate-to-Drain Charge		45			V _{GS} = 10V
Q _{sync}	Total Gate Charge Sync. (Qg- Qgd)		125			
$\mathbf{t}_{d(on)}$	Turn-On Delay Time		17			V _{DD} = 65V
t _r	Rise Time		97			I _D = 115A
$t_{d(off)}$	Turn-Off Delay Time		110		ns	$R_G = 2.7\Omega$
t_f	Fall Time		100			V _{GS} = 10V④
C _{iss}	Input Capacitance		9500			$V_{GS} = 0V$
C _{oss}	Output Capacitance		660			V _{DS} = 50V
C _{rss}	Reverse Transfer Capacitance		310		pF	f = 1.0MHz, See Fig.TBD
Coss eff.(ER)	Effective Output Capacitance (Energy Related)		725			V _{GS} = 0V, VDS = 0V to 80V®
Coss eff.(TR)	Output Capacitance (Time Related)		950			V _{GS} = 0V, VDS = 0V to 80V⑤

Diode Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
I _S	Continuous Source Current (Body Diode)			192		MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ①			690		integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 115A, V_{GS} = 0V $ ④
dv/dt	Peak Diode Recovery dv/dt3		18		V/ns	$T_J = 175^{\circ}C, I_S = 115A, V_{DS} = 100V$
4	Reverse Recovery Time		47		no	$T_J = 25^{\circ}C$ $V_{DD} = 85V$
t _{rr}	Reverse Recovery Time		55		ns	$T_J = 125^{\circ}C$ $I_F = 115A$,
	Deverse Deservery Charge		90			<u>T_J = 25°C</u> di/dt = 100A/μs ④
Q _{rr}	Reverse Recovery Charge		123		nC	<u>T_J = 125°C</u>
I _{RRM}	Reverse Recovery Current		3.5		Α	T _J = 25°C



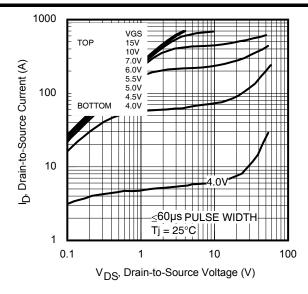


Fig 3. Typical Output Characteristics

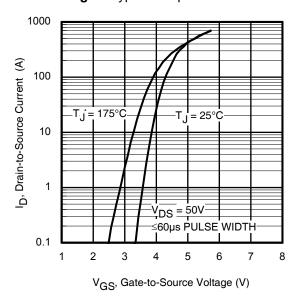


Fig 5. Typical Transfer Characteristics

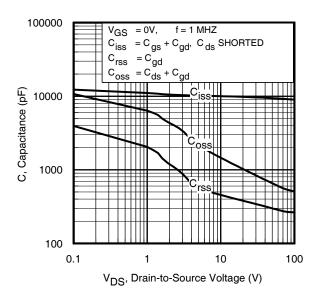


Fig 7. Typical Capacitance vs. Drain-to-Source Voltage

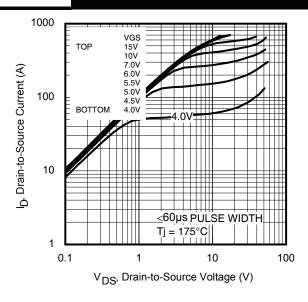


Fig 4. Typical Output Characteristics

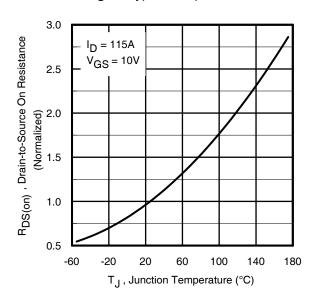


Fig 6. Normalized On-Resistance vs. Temperature

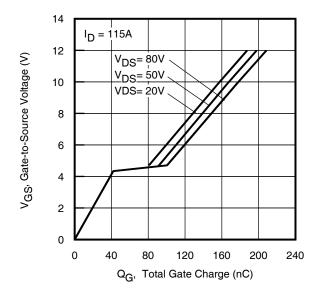


Fig 8. Typical Gate Charge vs.Gate-to-Source Voltage



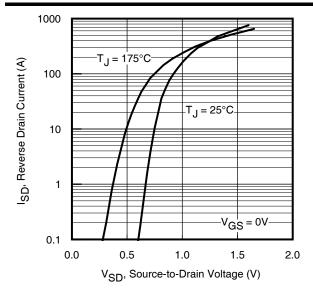


Fig 9. Typical Source-Drain Diode Forward Voltage

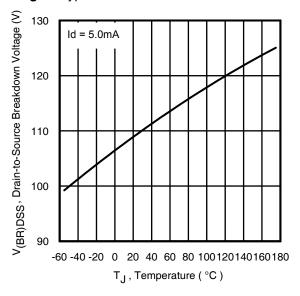


Fig 11. Drain-to-Source Breakdown Voltage

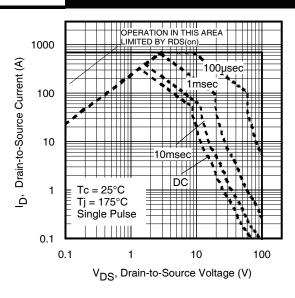


Fig 10. Maximum Safe Operating Area

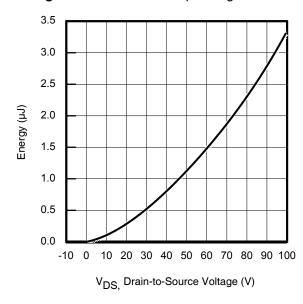


Fig 12. Typical Coss Stored Energy

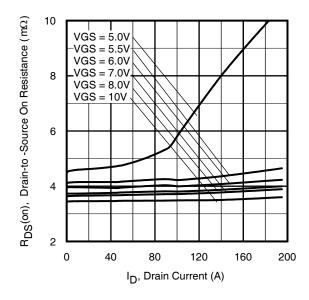


Fig 13. Typical On- Resistance vs. Drain Current



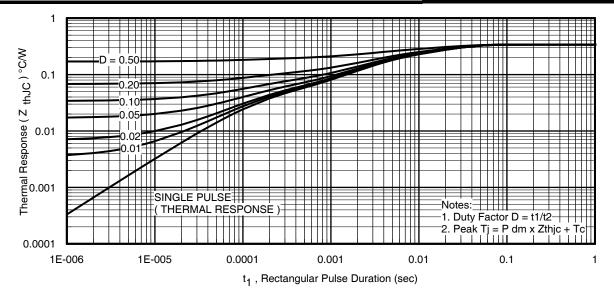


Fig 14. Maximum Effective Transient Thermal Impedance, Junction-to-Case

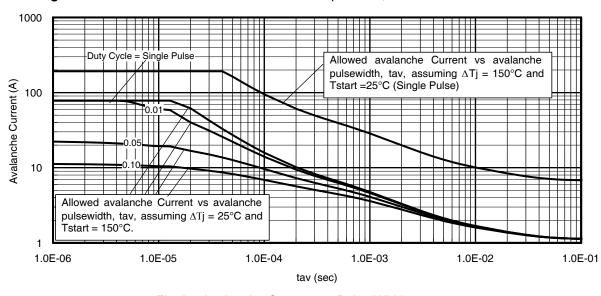


Fig 15. Avalanche Current vs. Pulse Width

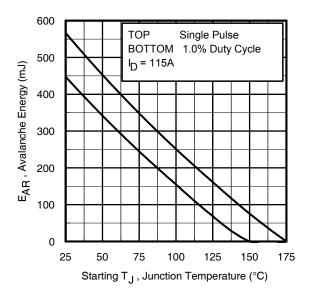


Fig 16. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 15, 16: (For further info, see AN-1005 at www.irf.com)

1. Avalanche failures assumption:

Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{imax}. This is validated for every

- 2. Safe operation in Avalanche is allowed as long $asT_{j\text{max}}$ is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 23a, 23b.
- 4. P_{D (ave)} = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I_{av} = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{imax} (assumed as 25°C in Figure 14, 15).

t_{av} = Average time in avalanche.

D = Duty cycle in avalanche = tav f

 $Z_{thJC}(D, t_{av})$ = Transient thermal resistance, see Figures 14) PD (ave) = 1/2 ($1.3 \cdot BV \cdot I_{av}$) = $\Delta T / Z_{thJC}$

 $I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$

 $E_{AS (AR)} = P_{D (ave)} t_{av}$



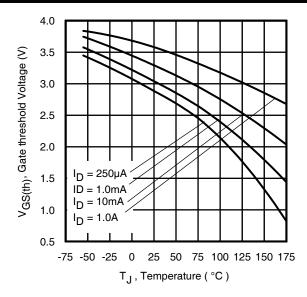


Fig 17. Threshold Voltage vs. Temperature

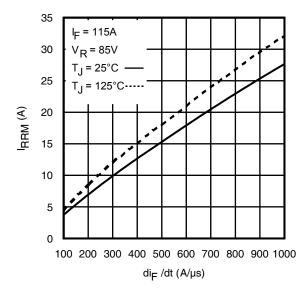


Fig 19. Typical Recovery Current vs. dif/dt

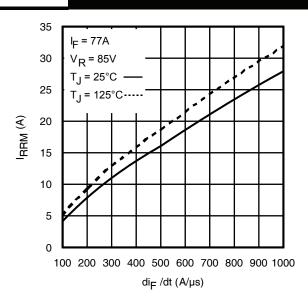


Fig 18. Typical Recovery Current vs. dif/dt

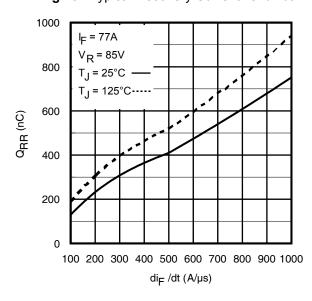


Fig 20. Typical Stored Charge vs. dif/dt

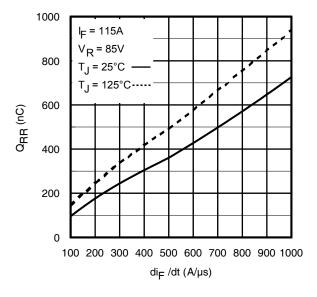


Fig 21. Typical Stored Charge vs. dif/dt

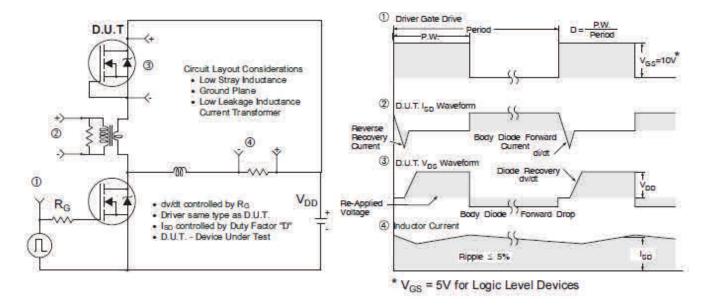


Fig 22. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

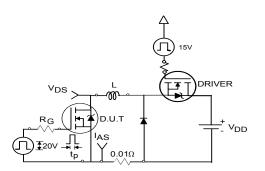


Fig 23a. Unclamped Inductive Test Circuit

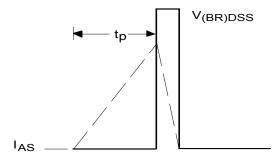


Fig 23b. Unclamped Inductive Waveforms

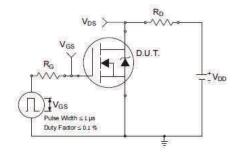


Fig 24a. Switching Time Test Circuit

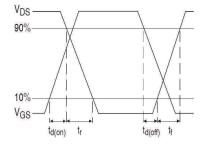


Fig 24b. Switching Time Waveforms

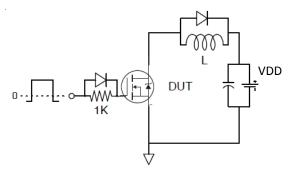


Fig 25a. Gate Charge Test Circuit

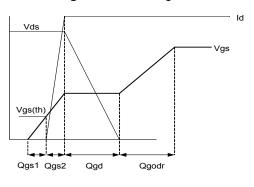
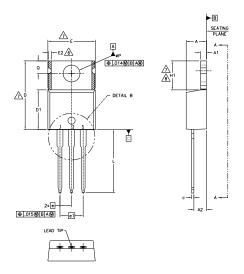
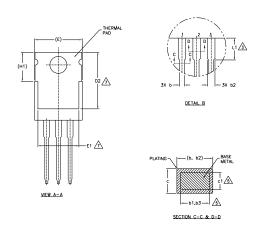


Fig 25b. Gate Charge Waveform



TO-220AB Package Outline (Dimensions are shown in millimeters (inches))





- DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994.
- DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].
- LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.
- DIMENSION D, D1 & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY.

- CONTROLLING DIMENSION: INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
- DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING 8.-AND SINGULATION IRREGULARITIES ARE ALLOWED.
- OUTLINE CONFORMS TO JEDEC TO-220, EXCEPT A2 (max.) AND D2 (min.) WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE.

SYMBOL	MILLIM	ETERS	INC	HES	
	MIN.	MAX.	MIN.	MAX.	NOTES
Α	3.56	4.83	.140	.190	
A1	1.14	1.40	.045	.055	
A2	2.03	2.92	.080	.115	
b	0.38	1.01	.015	.040	
b1	0.38	0.97	.015	.038	5
b2	1,14	1.78	.045	.070	
b3	1.14	1.73	.045	.068	5
С	0.36	0.61	.014	.024	
c1	0.36	0.56	.014	.022	5
D	14.22	16.51	.560	.650	4
D1	8.38	9.02	.330	.355	
D2	11.68	12.88	.460	.507	7
E	9.65	10.67	.380	.420	4,7
E1	6.86	8.89	.270	.350	7
E2	-	0.76	_	.030	8
е	2.54	BSC	.100	BSC	
e1	5.08	BSC	.200	BSC	
H1	5.84	6.86	.230	.270	7,8
L	12.70	14.73	.500	.580	
L1	3.56	4.06	.140	.160	3
øΡ	3.54	4.08	.139	.161	
Q	2.54	3.42	.100	.135	

LEAD ASSIGNMENTS

HEXFET

- 1.- GATE
- 2.- DRAIN 3.- SOURCE

IGBTs, CoPACK

- 1 GATE 2.- COLLECTOR 3.- EMITTER

DIODES

1.- ANODE 2.- CATHODE 3.- ANODE

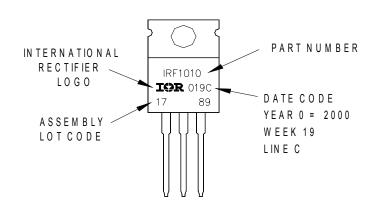
TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010

LOT CODE 1789

ASSEMBLED ON WW 19,2000 IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position indicates "Lead - Free"

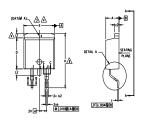


TO-220AB packages are not recommended for Surface Mount Application.

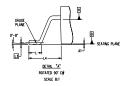
Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

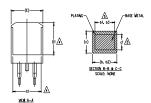


D²Pak (TO-263AB) Package Outline (Dimensions are shown in millimeters (inches))









- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S Y M		Ŋ			
В	MILLIM	ETERS	INC	HES	O T E S
0	MIN.	MAX.	MIN.	MAX.	S
Α	4.06	4.83	.160	.190	
A1	0.00	0.254	.000	.010	
b	0.51	0.99	.020	.039	
ь1	0.51	0.89	.020	.035	5
b2	1,14	1.78	.045	.070	
ь3	1,14	1.73	.045	.068	5
С	0.38	0.74	.015	.029	
c1	0.38	0.58	.015	.023	5
c2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	-	.270		4
Ε	9.65	10.67	.380	.420	3,4
E1	6.22		.245		4
е	2.54	BSC	.100	BSC	
Н	14.61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
L1	-	1.65	-	.066	4
L2	1.27	1.78	-	.070	
L3	0.25	BSC	.010	BSC	
L4	4.78	5.28	.188	.208	

LEAD ASSIGNMENTS

HEXFET

1.- GATE 2, 4.- DRAIN 3.- SOURCE

IGBTs, CoPACK

1.- GATE 2, 4.- COLLECTOR 3.- EMITTER

DIODES

1.- ANODE * 2, 4.- CATHODE 3 - ANODE

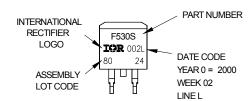
* PART DEPENDENT.

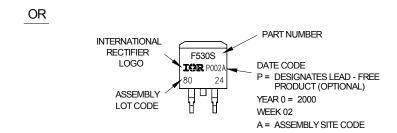
D²Pak (TO-263AB) Part Marking Information

EXAMPLE: THIS IS AN IRF530S WITH LOT CODE 8024

ASSEMBLED ON WW 02, 2000 IN THE ASSEMBLY LINE "L"

Note: "P" in assembly line position indicates "Lead - Free"

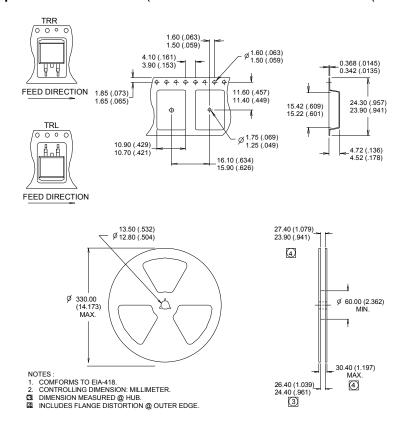




Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



D²Pak (TO-263AB) Tape & Reel Information (Dimensions are shown in millimeters (inches))



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification Information[†]

Qualification Level	Industrial (per JEDEC JESD47F) ††			
Moisture Sensitivity Level	TO-220	N/A		
	D ² Pak	MSL1		
RoHS Compliant	Yes			

† Qualification standards can be found at International Rectifier's web site: http://www.irf.com/product-info/reliability/



IR WORLD HEADQUARTERS: 101 N. Sepulveda Blvd., El Segundo, California 90245, USA

To contact International Rectifier, please visit http://www.irf.com/whoto-call/

Mouser Electronics

Authorized Distributor

Click to View Pricing, Inventory, Delivery & Lifecycle Information:

Infineon:

IRF100B201 IRF100S201